iCE40[™] LP Series Ultra Low-Power FPGA Family



October 03, 2012 (1.32)

Data Sheet

- LP-Series optimized for low power
- Ultra-small footprints
- 30% faster than iCE65
- Proven, high-volume 40 nm, low-power CMOS technology
- Integrated Phase-Locked Loop (PLL)
 - ◆ Clock multiplication/division for display, SerDes and memory interface applications
- Up to 533 MHz PLL Output
- Reprogrammable from a variety of methods and sources
- Flexible programmable logic and programmable interconnect fabric
 - ♦ 8K look-up tables (LUT4) and flip-flops
 - ♦ Low-power logic and interconnect
- Complete iCEcube2[™] development system
 - ♦ Windows® and Linux® support
 - ◆ VHDL and Verilog logic synthesis
 - Place and route software
 - Design and IP core libraries
 - Low-cost iCEman40LP development board

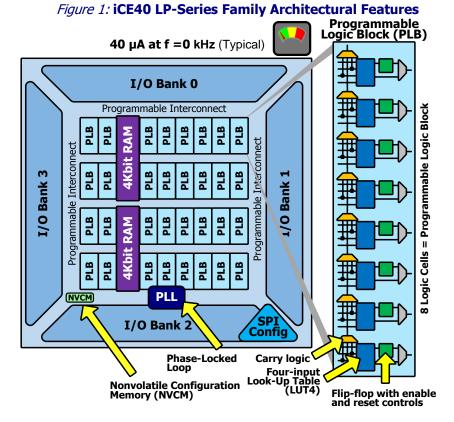


Table 1: iCE40LP Ultra Low-Power Programmable Logic Family Summary

	Part Nu	mber		LP1K	LP4K	LP8K
Logic Cells (LUT +	Flip-Flop)		1,280	3,520	7,680
RAM4K Memory Blo	ocks			16	20	32
RAM4K RAM bits		64K	80K	128K		
Phase-Locked Loop	s (PLLs)	1	2	2		
Configuration bits	(maximu	m)		245 Kb	533 Kb	1,057 Kb
Core Operating Pov	wer 0 KH:	z ¹		40 µA	140 µA	160 μΑ
Maximum Program	mable I/		95	167	178	
Maximum Differen	tial Input	Pairs		12	20	23
Package	Code	Area mm	Pitch mm	Prograi	nmable I/	O: Max
36 ² -ball ucBGA	CM36	2.5x2.5	0.4	25(3)		
49-ball ucBGA	CM49	3x3	0.4	35(5)		
81-ball ucBGA	CM81	4x4	0.4	63(8)	63(9) ³	
81-ball csBGA	CB81	5x5	0.5	62(8)		
121-ball ucBGA	CM121	5x5	0.4	95 (12)	93 (13)	93 (13)
121-ball csBGA	CB121	6x6	0.5	92 (12)		
225-ball ucBGA	CM225	7x7	0.4		167 (20)	178 (23)
84 ² -pin QFNS	QN84	7x7	0.5	67(7)		

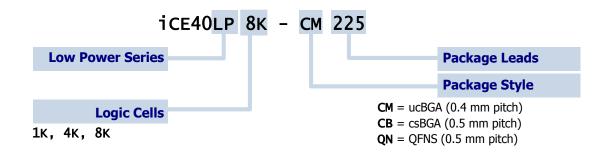
Note 1: At 1.2V VCC, 25°C Note 2: No PLL Available Note 3: Only 1 PLL Available



Ordering Information

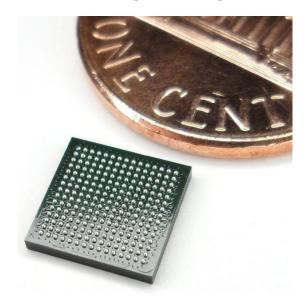
Figure 2 describes the iCE40LP ordering codes for all packaged components. See the separate DiePlus data sheets when ordering die-based products. See the separate iCE40 Pinout Excel files for package and pinout specifications.

Figure 2: iCE40P Ordering Codes (packaged, non-die components)



Part Number	LUTs	Supply Voltage	Temp.
iCE40LP1K-CM36	1,280	1.2V	IND
iCE40LP1K-CM49	1,280	1.2V	IND
iCE40LP1K-CM81	1,280	1.2V	IND
iCE40LP1K-CM121	1,280	1.2V	IND
iCE40LP1K-CB81	1,280	1.2V	IND
iCE40LP1K-CB121	1,280	1.2V	IND
iCE40LP1K-QN84	1,280	1.2V	IND
iCE40LP4K-CM81	3,520	1.2V	IND
iCE40LP4K-CM121	3,520	1.2V	IND
iCE40LP4K-CM225	3,520	1.2V	IND
iCE40LP8K-CM121	7,680	1.2V	IND
iCE40LP8K-CM225	7,680	1.2V	IND

iCE40LP8K-CM225 225-ball Chip-Scale BGA Package (7x7 mm footprint, 0.4 mm pitch)





Electrical Characteristics

All parameter limits are specified under worst-case supply voltage, junction temperature, and processing conditions.

Absolute Maximum Ratings

Stresses beyond those listed under Table 2 may cause permanent damage to the device. These are stress ratings only; functional operation of the device at these or any other conditions beyond those listed under the Recommended Operating Conditions is not implied. Exposure to absolute maximum conditions for extended periods of time adversely affects device reliability.

Table 2: Absolute Maximum Ratings

Symbol	Description	Minimum	Maximum	Units
VCC	Core supply Voltage	-0.5	1.42	V
VPP_2V5	VPP_2V5 NVCM programming and operating supply			V
VPP_FAST	Optional fast NVCM programming supply			V
VCCIO_0 VCCIO_1 VCCIO_2 VCCIO_3 SPI_VCC	I/O bank supply voltage (I/O Banks 0, 1, 2 and 3 plus SPI interface)	4.00	V	
VIN_0 VIN_1 VIN_2 VIN_SPI VIN_3	Voltage applied to PIO pin within a specific I/O bank (I/O Banks 0, 1, 2 and 3 plus SPI interface)	-1.0	3.6	V
VCCPLL	Analog voltage supply to the Phase Locked Loop (PLL)	-0.5	1.30	V
I _{out}	DC output current per pin	_	20	mA
T ₃	Junction temperature	– 55	125	°C
T _{STG}	Storage temperature, no bias	- 65	150	°C

Recommended Operating Conditions

Table 3: Recommended Operating Conditions

Symbol	Desci	ription	Minimum	Nominal	Maximum	Units
VCC	Core supply voltage	High Performance, low-power	1.14	1.20	1.26	V
VPP_2V5 ¹	VPP_2V5 NVCM	Release from Power-on Reset	1.30	_	3.47	V
	programming and operating	Configure from NVCM	2.30	_	3.47	V
	supply	NVCM programming	2.30	_	3.00	V
VPP_FAST ²	Optional fast NVCM programm	ing supply	Leave	unconnecte	d in application	า
SPI_VCC	SPI interface supply voltage	1.71	_	3.47	V	
VCCIO_0	I/O standards, all banks	LVCMOS33	2.70	3.30	3.47	V
VCCIO_1		LVCMOS25, LVDS	2.38	2.50	2.63	V
VCCIO_2 VCCIO_3		LVCMOS18, SubLVDS	1.71	1.80	1.89	V
SPI_VCC		LVCMOS15	1.43	1.50	1.58	٧
VCCPLL ³	Analog voltage supply to the P	hase Locked Loop (PLL)	1.14	1.20	1.26	V
T _A	Ambient temperature		-4 0	_	85	°C
T _{PROG}	NVCM programming temperati	ure	10	25	30	°C

Notes:

- 1. VPP_2V5 must be connected to a valid voltage, when the iCE40LP device is active.
- 2. VPP_FAST, used only for fast production programming, must be left floating or unconnected in application, except CM36 and CM49 packages MUST have VPP_FAST ball connected to VCCIO_0 ball externally.
- 3. VCCPLL must be tied to VCC when PLL is not used.



I/O Characteristics

Table 4: PIO Pin Electrical Characteristics

Symbol	Description	Conditions	Minimum	Nominal	Maximum	Units
$\mathbf{I_l}$	Input pin leakage current	$V_{IN} = VCCIO_{max}$ to 0 V			±10	μA
I _{oz}	Three-state I/O pin (Hi-Z) leakage current	$V_{O} = VCCIO_{max}$ to 0 V			±10	μΑ
C _{PIO}	PIO pin input capacitance			6		pF
C _{GBIN}	GBIN global buffer pin input capacitance			6		pF
R _{PULLUP}	Internal PIO pull-up	VCCIO = 3.3V		60		kΩ
	resistance during	VCCIO = 2.5V		80		kΩ
	configuration	VCCIO = 1.8V		120		kΩ
		VCCIO = 1.5V		160		kΩ
V _{HYST}	Input hysteresis	VCCIO = 1.5V to 3.3V		50		mV

NOTE: All characteristics are characterized and may or may not be tested on each pin on each device.

Single-ended I/O Characteristics

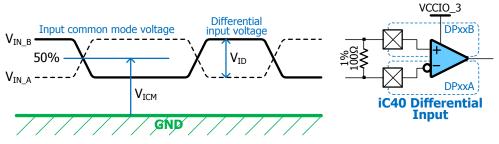
Table 5: I/O Characteristics

	Nominal I/O Bank Supply	Input Vo	ltage (V)	Output Vo	oltage (V)	Output Current at Voltage (mA)		
I/O Standard	Voltage	V_{IL}	V _{IH}	V _{oL}	V _{OH}	I _{oL}	I _{OH}	
LVCMOS33	3.3V	0.80	2.00	0.4	2.40	8	8	
LVCMOS25	2.5V	0.70	1.70	0.4	2.00	6	6	
LVCMOS18	1.8V	35% VCCIO	65% VCCIO	0.4	1.40	4	4	
LVCMOS15	1.5V	35% VCCIO	65% VCCIO	0.4	1.20	2	2	



Differential Inputs

Figure 3: Differential Input Specifications



Input common mode voltage:

$$V_{ICM} {=} \frac{VCCIO_3}{2} \pm \Delta V_{ICM}$$

Differential input voltage:

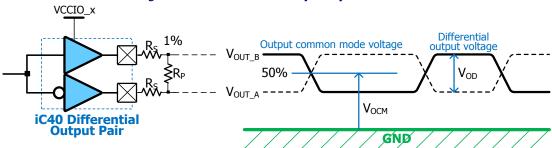
$$V_{ID} = |V_{IN_B} - V_{IN_A}|$$

Table 6: Recommended Operating Conditions for Differential Inputs

I	/ 0	VCCIO_3 (V)			V _{ID} (mV)			V _{ICM} (V)			
Star	ndard	Min	Nom	Max	Min	Nom	Max	Min	Nom	Max	
LV	/DS	2.38	2.50	2.63	250	350	450	$\frac{\text{VCCIO}_3}{2} - 0.30$	VCCIO_3	$\frac{\text{VCCIO}_3}{2} + 0.30$	
Sub	LVDS	1.71	1.80	1.89	100	150	200	$\frac{\text{VCCIO}_3}{2} - 0.25$	VCCIO_3	$\frac{\text{VCCIO}_3}{2} + 0.25$	

Differential Outputs

Figure 4: Differential Output Specifications



Output common mode voltage:

$$V_{OCM} = \frac{VCCIO_x}{2} \pm \Delta V_{OCM}$$

Differential output voltage:

$$V_{OD} = |V_{OUT_B} - V_{OUT_A}|$$

Table 7: Recommended Operating Conditions for Differential Outputs

I/O	VCCIO_x (V)			Ω		V _{op} (mV)		V _{OCM} (V)			
Standard	Min	Nom	Max	Rs	R _P	Min	Nom	Max	Min	Nom	Max
LVDS	2.38	2.50	2.63	150	140	300	350	400	$\frac{\text{VCCIO}}{2} - 0.15$	$\frac{\text{VCCIO}}{2}$	$\frac{\text{VCCIO}}{2} + 0.15$
SubLVDS	1.71	1.80	1.89	270	120	100	150	200	$\frac{\text{VCCIO}}{2} - 0.10$	$\frac{\text{VCCIO}}{2}$	$\frac{\text{VCCIO}}{2} + 0.10$



AC Timing Guidelines

The following examples provide some guidelines of device performance. The actual performance depends on the specific application and how it is physically implemented in the iCE40 FPGA using the Lattice iCEcube2 software. The following guidelines assume typical conditions (VCC = 1.0 V or 1.2 V as specified, temperature = $25 \,^{\circ}$ C). Apply derating factors using the iCEcube2 timing analyzer to adjust to other operating regimes.

Programmable Logic Block (PLB) Timing

Table 8 provides timing information for the logic in a Programmable Logic Block (PLB), which includes the paths shown in Figure 5 and Figure 6.

PAD PIO PAD LUT4 Logic Cell

Figure 6 PLB Combinational Timing Circuit

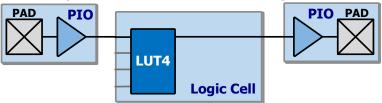


Table 8: Typical Programmable Logic Block (PLB) Timing

			Nominal VCC	1.2 V	
			Description	Тур.	units
Sequen	tial Logic	Paths			
F _{TOGGLE}	GBIN input	GBIN input	Flip-flop toggle frequency. DFF flip-flop output fed back to LUT4 input with 4-input XOR, clocked on same clock edge	256	MHz
t _{cKO}	DFF clock input	PIO output	Logic cell flip-flop (DFF) clock-to-output time, measured from the DFF CLK input to PIO output, including interconnect delay.	5.5	ns
t _{GBCKLC}	GBIN input	DFF clock input	Global Buffer Input (GBIN) delay, though Global Buffer (GBUF) clock network to clock input on the logic cell DFF flip-flop.	2.1	ns
t _{SULI}	PIO input	GBIN input	Minimum setup time on PIO input, through LUT4, to DFF flip-flop D-input before active clock edge on the GBIN input, including interconnect delay.	0.9	ns
t _{HDLI}	GBIN input	PIO input	Minimum hold time on PIO input, through LUT4, to DFF flip-flop D-input after active clock edge on the GBIN input, including interconnect delay.	0	ns
Combin	ational L	ogic Pat	ths		
t _{LUT4IN}	PIO input	LUT4 input	Asynchronous delay from PIO input pad to adjacent PLB interconnect.	2.5	ns
t _{ILO}	LUT4 input	LUT4 output	Logic cell LUT4 combinational logic propagation delay, regardless of logic complexity from input to output.	0.48	ns
t _{LUT4IN}	LUT4 output	PIO output	Asynchronous delay from adjacent PLB interconnect to PIO output pad.	5.1	ns



Programmable Input/Output (PIO) Block

Table 9 provides timing information for the logic in a Programmable Logic Block (PLB), which includes the paths shown in Figure 7 and Figure 8. The timing shown is for the LVCMOS25 I/O standard in all I/O banks. The iCEcube2 development software reports timing adjustments for other I/O standards.

Figure 7: Programmable I/O (PIO) Pad-to-Pad Timing Circuit

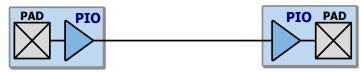


Figure 8: Programmable I/O (PIO) Sequential Timing Circuit

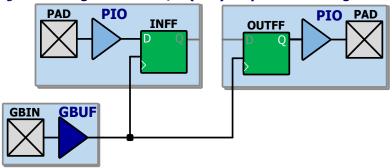


Table 9: Typical Programmable Input/Output (PIO) Timing (LVCMOS25)

_	Table 31 Typical Frogrammable Impacy Galepac (F20) Timing (21 of 10020)									
			Nominal VCC	1.2 V						
			Description	Тур.	units					
Synchro	nous Out	put Path	s							
t _{ocko}	OUTFF	PIO	Delay from clock input on OUTFF output flip-flop to PIO output	4.3	ns					
	clock	output	pad.							
	input									
t _{GBCKIO}	GBIN	OUTFF	Global Buffer Input (GBIN) delay, though Global Buffer (GBUF)	2.0	ns					
	input	clock	clock network to clock input on the PIO OUTFF output flip-flop.							
		input								
Synchro	nous Inp	ut Paths								
t _{SUPDIN}	PIO	GBIN	Setup time on PIO input pin to INFF input flip-flop before active	0	ns					
	input	input	clock edge on GBIN input, including interconnect delay.							
t _{HDPDIN}	GBIN	PIO	Hold time on PIO input to INFF input flip-flop after active clock	2.2	ns					
	input	input	edge on the GBIN input, including interconnect delay.							
Pad to P	ad									
t _{PADIN}	PIO	Inter-	Asynchronous delay from PIO input pad to adjacent	2.5	ns					
	input	connect	interconnect.							
t _{PADO}	Inter-	PIO	Asynchronous delay from adjacent interconnect to PIO output	4.8	ns					
	connect	output	pad including interconnect delay.							



RAM4K Block

Table 10 provides timing information for the logic in a RAM4K block, which includes the paths shown in Figure 9.

Figure 9: RAM4K Timing Circuit

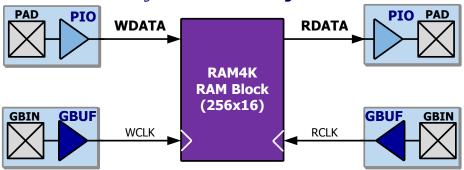


Table 10: Typical RAM4K Block Timing

			Nominal VCC	1.2 V	
			Description	Тур.	
Write Se	tup/Hole	d Time			
t _{SUWD}	PIO input	GBIN input	Minimum write data setup time on PIO inputs before active clock edge on GBIN input, include interconnect delay.	0.62	ns
t _{HDWD}	GBIN input	PIO input	Minimum write data hold time on PIO inputs after active clock edge on GBIN input, including interconnect delay.	0	ns
Read Clo	ck-Outp	ut-Time			
t _{CKORD}	RCLK clock input	PIO output	Clock-to-output delay from RCLK input pin, through RAM4K RDATA output flip-flop to PIO output pad, including interconnect delay.	5.6	ns
t _{GBCKRM}	GBIN input	RCLK clock input	Global Buffer Input (GBIN) delay, though Global Buffer (GBUF) clock network to the RCLK clock input.	2.0	ns
Write an	d Read (Clock Ch	aracteristics		
t _{RMWCKH}	WCLK	WCLK	Write clock High time	0.42	ns
t _{RMWCKL}	RCLK	RCLK	Write clock Low time	0.48	ns
t _{RMWCYC}			Write clock cycle time	0.98	ns
F _{WMAX}			Sustained write clock frequency	256	MHz



Phase-Locked Loop (PLL) Block

Table 11 provides timing information for the Phase-Locked Loop (PLL) block shown in Figure 10.

Figure 10: Phase-Locked Loop (PLL)

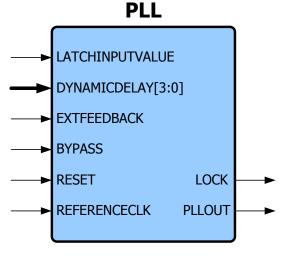


Table 11: Phase-Locked Loop (PLL) Block Timing

Table 11. Phase-Locked Loop (PLL) Block Tilling											
			Nominal VCC		1.2 V						
Symbol	From	To	Description	Min.	Typical	Max.	Units				
Frequenc	y Range										
F _{REF}			Input clock frequency range	10	_	133	MHz				
F _{OUT}			Output clock frequency range (cannot exceed maximum frequency supported by global buffers)	16	_	533	MHz				
Duty Cyc	le										
PLL _{IJ}			Input duty cycle	35	_	65	%				
Tw _{HI}			Input clock high time	2.5	_	_	ns				
Tw _{LOW}			Input clock low time	2.5	_	_	ns				
PLL _{OJ}			Output duty cycle	45	_	55	%				
Fine Dela	ay										
t fdtap			Fine delay adjustment, per tap		165		ps				
PLL _{TAPS}			Fine delay adjustment settings	0		15	taps				
PLL _{FDAM}			Maximum delay adjustment		2.5		ns				
Jitter											
PLL_{IPJ}			Input clock period jitter	_	_	+/- 300	ps				
PLL _{OPJ}			PLLOUT output period jitter	_	1% or ≤ 100	+/- 1.1% output period or ≥ 110	ps				
Lock/Res	set Time										
t _{LOCK}			PLL lock time after receive stable, monotonic REFERENCECLK input	_	_	50	μs				
tw _{RST}			Minimum reset pulse width	20	_	_	ns				

Notes:

- 1. Output jitter performance is affected by input jitter. A clean reference clock < 100ps jitter must be used to ensure best jitter performance.
- 2. The output jitter specification refers to the intrinsic jitter of the PLL.



Internal Configuration Oscillator Frequency

Table 12 shows the operating frequency for the iCE40's internal configuration oscillator.

Table 12: Internal Oscillator Frequency at VCC = 1.2V

	Oscillator	Frequency (MHz)		
Symbol	Mode	Min.	Max.	Description
f _{OSCD}	Default	7	10	Default oscillator frequency. Slow enough to safely operate with any SPI serial PROM.
f _{OSCL}	Low Frequency	21	30	Supported by most SPI serial Flash PROMs
f _{OSCH}	High Frequency	35	50	Supported by some high-speed SPI serial Flash PROMs
	Off	0	0	Oscillator turned off by default after configuration to save power.

Configuration Timing

Table 13 shows the maximum time to configure an iCE40LP device, by oscillator mode. The calculations use the slowest frequency for a given oscillator mode from Table 12 and the maximum configuration bitstream size from Table 1, which includes full RAM4K block initialization. The configuration bitstream selects the desired oscillator mode based on the performance of the configuration data source.

Table 13: Typical SPI Master or NVCM Configuration Timing by Oscillator Mode

Symbol	Description	Device	Default	Low Freq.	High Freq.	Units
t _{CONFIGL}	Time from when minimum	iCE40LP1K	53	25	11	ms
	Power-on Reset (POR)	iCE40LP4K	230	110	50	ms
	threshold is reached until user application starts.	iCE40LP8K	230	110	50	ms

Table 14 provides timing for the CRESET_B and CDONE pins.

Table 14: General Configuration Timing

				All Grades		
Symbol	From	То	Description	Min.	Max.	Units
t _{CRESET_B}	CREST_B	CREST_B	Minimum CRESET_B Low pulse width required to restart configuration, from falling edge to rising edge	200	_	ns
t _{DONE_IO}	CDONE High	PIO pins active	Number of configuration clock cycles after CDONE goes High before the PIO pins are activated.	_	49	Clock cycles
			SPI Peripheral Mode (Clock = SPI_SCK, cycles measured rising-edge to rising-edge)		nds on frequency	

Table 15 provides various timing specifications for the SPI peripheral mode interface.

Table 15: SPI Peripheral Mode Timing

	rable 157 of 11 of priority from 1						
				All Grades			
Symbol	From	То	Description	Min.	Max.	Units	
t _{CR_SCK}	CRESET_B	SPI_SCK	Minimum time from a rising edge on CRESET_B until the first SPI write operation, first SPI_SCK. During this time, the iCE40LP FPGA is clearing its internal configuration memory	300	_	μs	
t _{SUSPISI}	SPI_SI	SPI_SCK	Setup time on SPI_SI before the rising SPI_SCK clock edge	12	_	ns	
t _{HDSPISI}	SPI_SCK	SPI_SI	Hold time on SPI_SI after the rising SPI_SCK clock edge	12	_	ns	
t _{SPISCKH}	SPI_SCK	SPI_SCK	SPI_SCK clock High time	20	_	ns	
t _{SPISCKL}	SPI_SCK	SPI_SCK	SPI_SCK clock Low time	20	_	ns	
t _{SPISCKCYC}	SPI_SCK	SPI_SCK	SPI_SCK clock period*	40	1,000	ns	
F _{SPI_SCK}	SPI_SCK	SPI_SCK	Sustained SPI_SCK clock frequency*	1	25	MHz	

^{* =} Applies after sending the synchronization pattern.



Power Consumption Characteristics

Core Power

Table 16 shows the power consumed on the internal VCC supply rail when the device is filled with 16-bit binary counters, measured with a 32.768 kHz and at 32.0 MHz

Table 16: VCC Power Consumption for Device Filled with 16-Bit Binary Counters

			iCE40LP1K	iCE40LP4K	iCE40LP8K	
Symbol	Description	VCC	Typical ¹	Typical ¹	Typical ¹	Units
I _{CCOK}	f =0	1.2V	40	140	160	μA
I _{CC32K}	f ≤ 32.768 kHz	1.2V	44	156	178	μΑ
I _{CC32M}	f = 32.0 MHz	1.2V	3	11	12	mA

Note 1: At 25°C

I/O Power

Table 17 provides the static current by I/O bank. The typical current for I/O Banks 0, 1, 2 and the SPI bank is not measurable within the accuracy of the test environment. The PIOs in I/O Bank 3 use different circuitry and dissipate a small amount of static current.

Table 17: I/O Bank Static Current (f = 0 MHz)

Symbol		Description	Typical	Maximum	Units
I _{cco o}	I/O Bank 0	Static current consumption per I/O bank.	« 1		uA
I _{cco 1}	I/O Bank 1	f = 0 MHz. No PIO pull-up resistors	« 1		uA
I _{cco 2}	I/O Bank 2	enabled. All inputs grounded. All	« 1		uA
I _{CCO_3}	I/O Bank 3	outputs driving Low.	« 1		uA
I _{CCO SPI}	SPI Bank		« 1		uA

NOTE: The typical static current for I/O Banks 0, 1, 2, and the SPI bank is less than the accuracy of the device tester.

Power Estimator

To estimate the power consumption for a specific application, please download and use the iCE40LP Power Estimator Spreadsheet or use the power estimator built into the iCEcube2 software.

iCE40 LP Series Ultra-Low Power Family



Revision History

Version	Date	Description
1.32	03-OCT-2012	Updated Table 1 to remove iCE40LP640, add packages CB81 and CB121, note 1 to include 25°C, and unified package nomenclature. Updated Figure 2 Ordering codes to include all part numbers. Added Note 1: At 25°C to Table 16 VCC Power.
1.31	30-MAR-2012	Updated Table 1
1.3	22-MAR-2012	Production Release. Updated Notes on Table 3: Recommended Operating Conditions Updated values in Table 4, Table 5, Table 12, Table 13 and Table 17
1.21	5-MAR-2012	Updated Figure 3 and Figure 4 to specify iCE40
1.2	13-FEB-2012	Updated company name
1.1	15-DEC-2011	Moved package specifications to iCE40 Pinout Excel files. Updated Table 1 maximum IOs.
1.01	31-OCT-2011	Added 640, 1K and 4K to Table 13 configuration times. Updated Table 1 maximum IOs.
1.0	11-JUL-2011	Initial Release

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